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Form PTO-1449 Modified List of Patent and Publications Cited by Applicant (Use several sheets if necessary) U.S. Department of Commerce Patent and Trademark Office				Docket No. CACS-0017		Serial No. 09/786,176	
				Applicant David Edward Williams et al.			
				Filing Date November 13, 2001		Group 2856	
FOREIGN PATENT DOCUMENTS							
Examiner Initial		Document No.	Date	Country	Translation		
					YES	NO	
72P	AI	150454/1991	06/26/91	JP	X		
	AJ	65662/1992	03/02/92	JP	X		
	AK	145354/1992	05/19/92	JP	X		
72P	AL	302903/1993	11/16/93	JP	X		
EXAMINER 72P				DATE CONSIDERED 6/28/02			



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		Applicant David Edward Williams et al.	
		Filing Date November 13, 2001	Group Not yet assigned
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)			
92P	AA	Gurlo et al., "In ₂ O ₃ and MoO ₃ -In ₂ O ₃ thin film semiconductor sensor: Interaction with NO ₂ and O ₃ ," <i>Sensors & Actuators B: Chemical</i> , 1998, 47, 92-99	
	AB	Heilig, A. et al., "Gas identification by modulating temperatures of SnO ₂ -based thick film sensors," <i>Sensors and Actuators B: Chemical</i> , 1997, 43(1-3), 45-51	
	AC	Takada et al., "Highly sensitive ozone sensor," <i>Sensors & Actuators B: Chemical</i> , 1993, 13-14, 404-407	
92P	AD	International Search Report dated January 12, 2000, issued in the corresponding PCT Application No. PCT/GB99/02757	
EXAMINER 92P		DATE CONSIDERED 6/27/02	



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U. S. PATENT DOCUMENTS

Examiner Initial		Document No.	Date	Name	Class	Subclass
72P	AE	4,627,269	12/09/86	Forster et al.	73	23

FOREIGN PATENT DOCUMENTS

Examiner Initial		Document No.	Date	Country	Translation YES NO	
72P	AF	43 16 970 C	08/25/94	DE	X abstract only	
72P	AG	EP 0 775 912	05/28/97	EP	X abstract only	
72P	AH	95/35495 A	12/28/95	WO		
EXAMINER 72P				DATE CONSIDERED 6/27/02		